UNI 580

The UNI580 is specially designed for a mass DDR, DDR2 and DDR3 component testing. UNI580 provides a high speed interface up to 880Mbps data rate, which makes it possible to test large volume like 512 DUTs for x4/x8 and 256 DUTs for x16 at one station. When broaden at 2 stations, UNI580 supports up to 1024 DUTs.

Optimized Memory Testing Solution for Mass Production

UNI 580

General Feature

-Supports DDR, DDR2 and DDR3 SDRAM
-Variable frequency up to 440MHz [880Mbps]
-Supports 512DUTs parallel test at one station [1024DUTs at two stations].
-Optimizing setup/hold time of address and data at write cycle and read cycle as frequency changing
-Variable test voltages [VDD, VDDQ, VTT, VREF]
-Leakage, ICC measurement
-Built in bitmap and shmoo factions for analysis.
-Graphical and text style logging
-Fully automated handler interfaced for mass production

Specification

Memory Types Supported	DDR SDRAM, DDR2 SDRAM, DDR3 SDRAM
Test Frequency	440MHz [880Mbps]
Parallel Test	512 DUTs/system
ALPG	Real time Algorithmic Patten Generator
Test Pattern	Programmable
Analysis Tool	Fail address & DQ map, Shmoo Plot, IO masking
Automated System [optional]	Vertical Memory Handler

∗ Specifications may be changed without notification